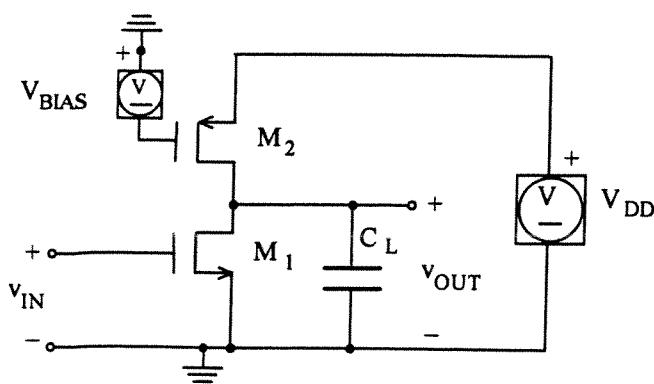


## PROPERTIES BASIC AMPLIFIERS

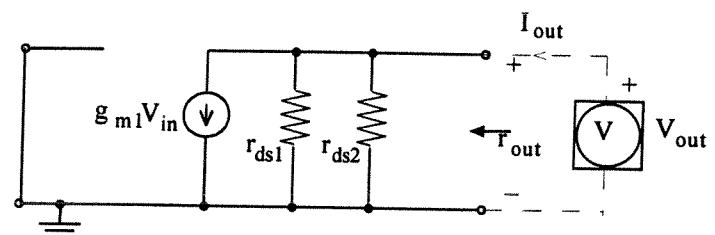
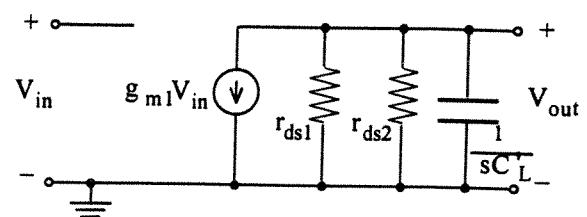
	<b>COMMON SOURCE (CS)</b>	<b>COMMON DRAIN (CD)</b>	<b>COMMON GATE (CG)</b>	<b>CMOS INVERTER (CI)</b>
<b>Voltage-gain</b>	high (inv.)	low (<1) (non-inv.)	high (non- inv.)	high (inv.)
<b>Output resistance</b>	high	low	high	high
<b>Input resistance</b>	high	high	low	high
<b>Application areas</b>	inp.stage OP	outp.stage OP	low-resistance inp.stage (signal from transmission line)	uncommon sensitive hard to design

	<b>CS</b>	<b>CD</b>	<b>CG</b>	<b>CI</b>
$A_o$	$-\frac{g_{m1}}{g_{out}}$	$\frac{g_m}{g_{out}} \approx 1$	$\frac{g_{m1} + g_{b1}}{g_{out}} \approx \frac{g_{m1}}{g_{out}}$	$-\frac{g_{m1} + g_{m2}}{g_{out}}$
$P_1$	$-\frac{g_{out}}{C_L}$	$-\frac{g_{out}}{C_L}$	$-\frac{g_{out}}{C_L}$	$-\frac{g_{out}}{C_L}$
$\omega_u$	$\frac{g_{m1}}{C_L}$	$\frac{g_{m1}}{C_L}$	$\approx \frac{g_{m1}}{C_L}$	$\frac{g_{m1} + g_{m2}}{C_L}$
$g_{out}$	$g_{ds1} + g_{ds2}$	$g_{m1} + g_{b1} + g_{ds1} + g_{ds2}$	$g_{ds1} + g_{ds2}$	$g_{ds1} + g_{ds2}$
$g_{in}$	0	0	$g_{m1} \cdot \frac{1}{1 + \frac{g_{ds1}}{g_{ds2}}}$	0

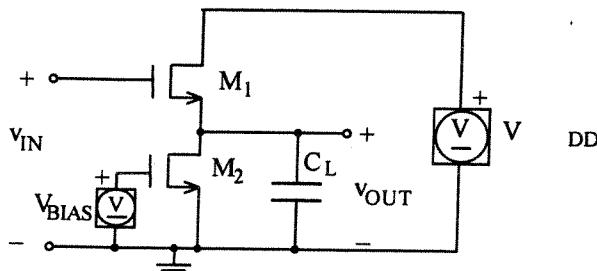
**34**  
**COMMON SOURCE AMPLIFIER**



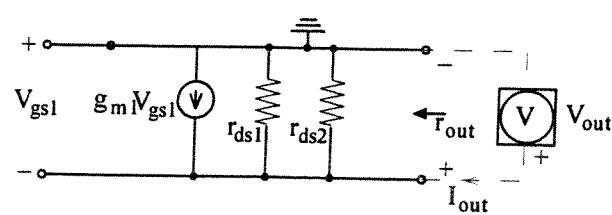
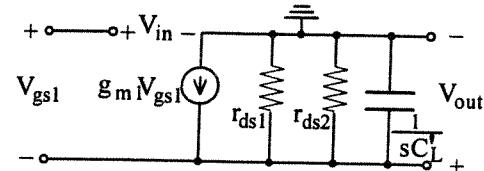
**SMALL-SIGNAL EQUIVALENT CIRCUIT  
(SSEC)**



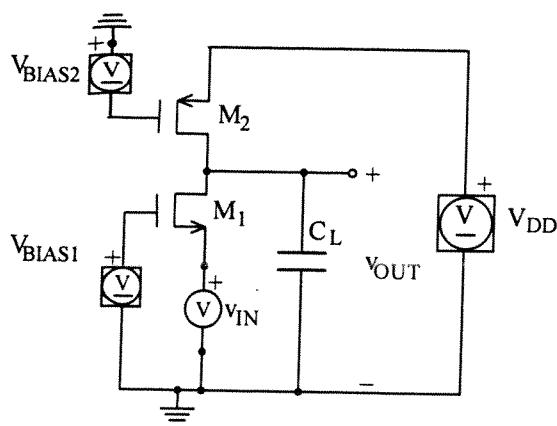
**COMMON DRAIN AMPLIFIER**



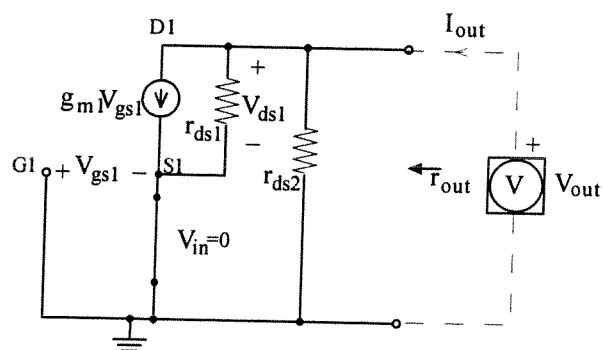
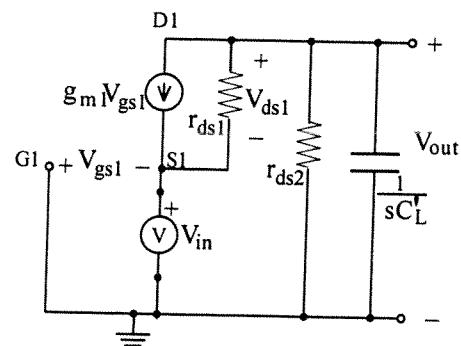
**SMALL-SIGNAL EQUIVALENT CIRCUIT  
(SSEC)**



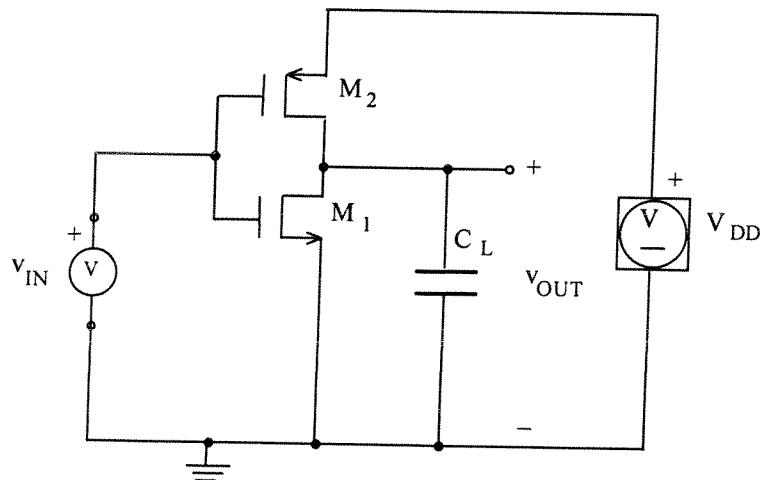
### C05 MONO GATE AMPLIFIER



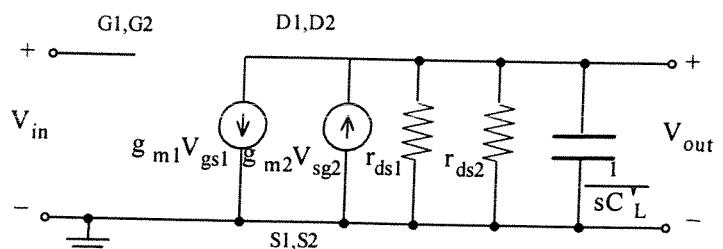
### SMALL-SIGNAL EQUIVALENT CIRCUIT (SSEC)



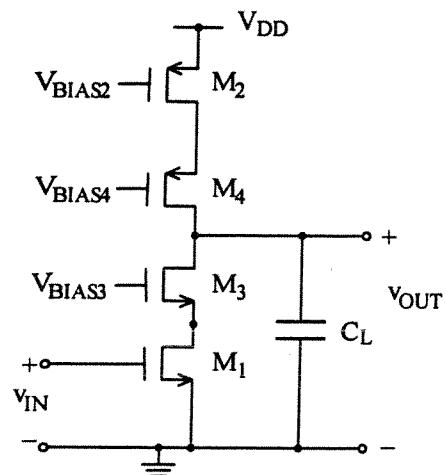
### CMOS-INVERTER



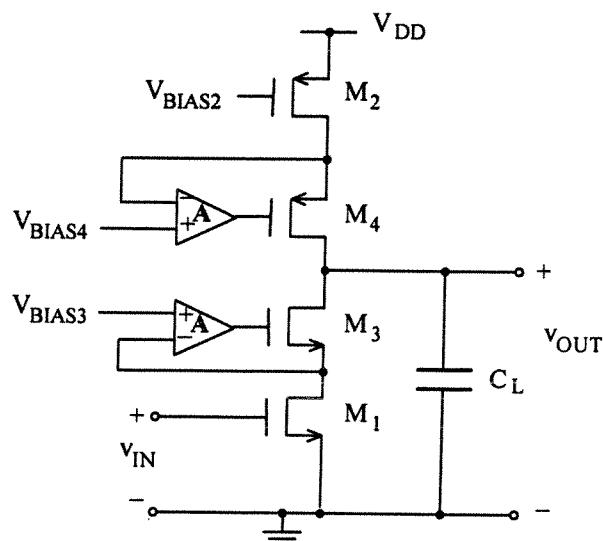
### SMALL-SIGNAL EQUIVALENT CIRCUIT (SSEC)



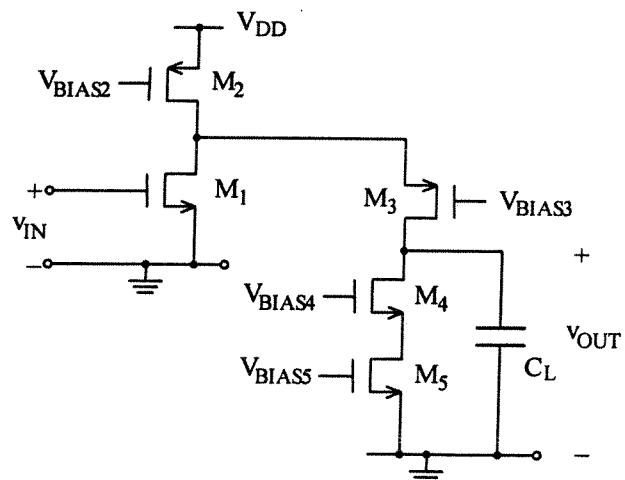
**COMMON SOURCE AMPLIFIER  
WITH CASCODE**



**COMMON SOURCE AMPLIFIER  
WITH CASCODE. EXTRA BIAS**

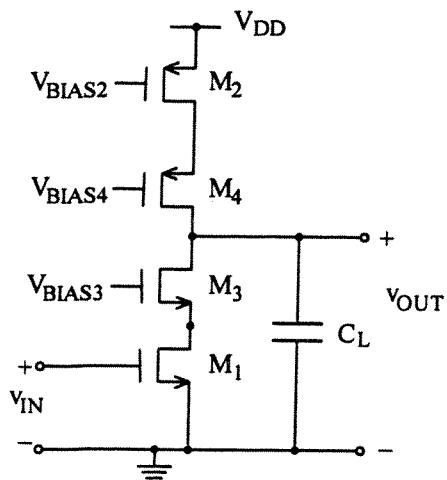


**COMMON SOURCE AMPLIFIER  
WITH FOLDED CASCODE**



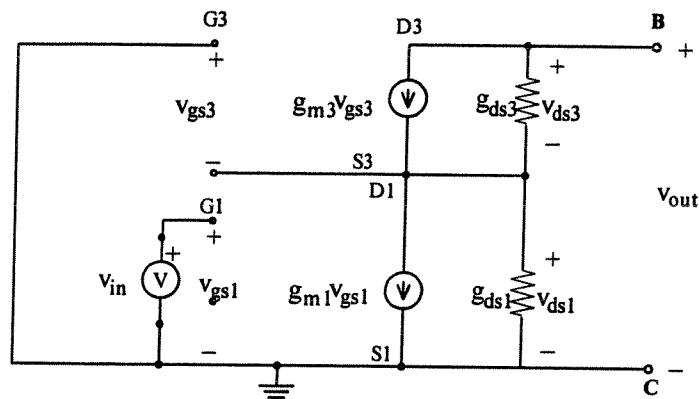
## COMMON SOURCE AMPLIFIER

### 37 WITH CASCODE



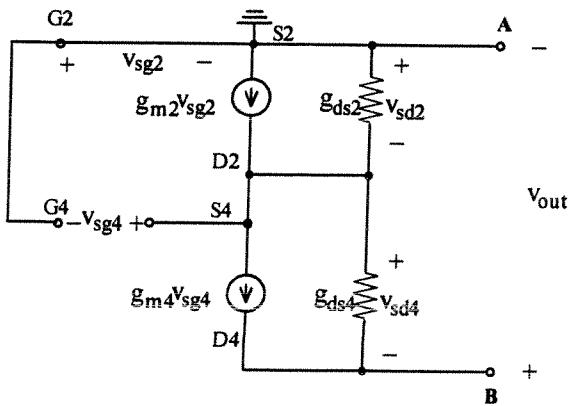
SSEC

NMOS-part



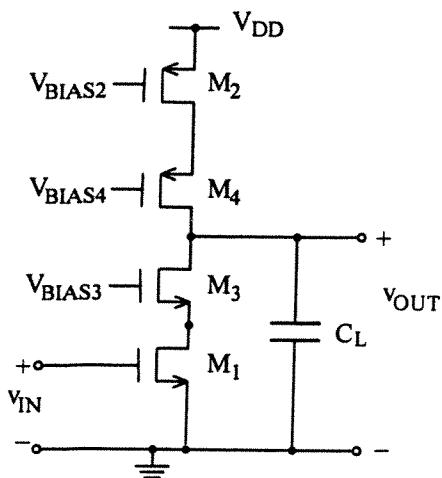
SSEC

PMOS-part



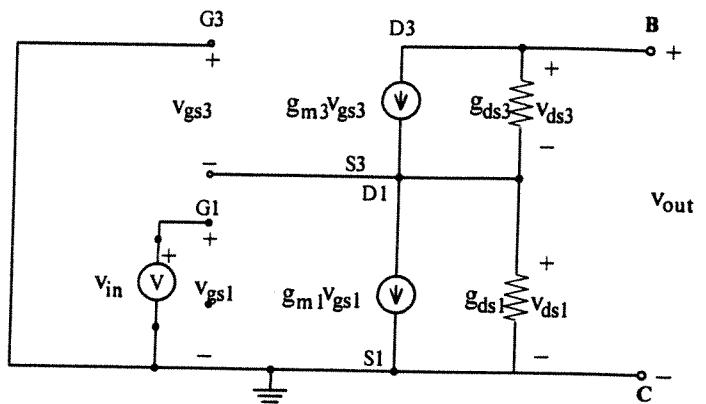
# COMMON SOURCE AMPLIFIER

38 WITH CASCODE



SSEC

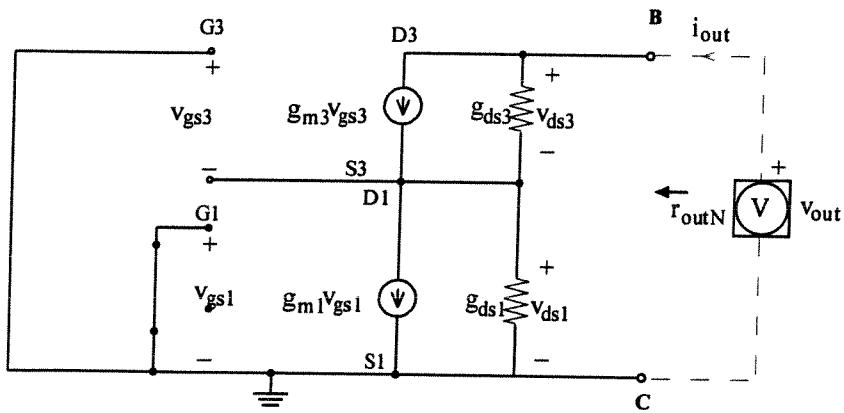
NMOS-part



Determine  $r_{out}$

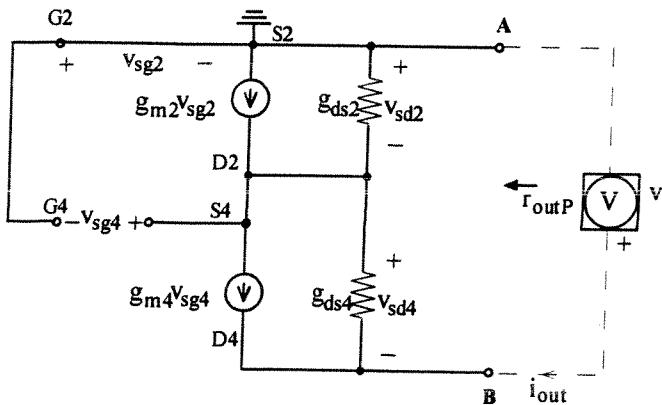
SSEC

NMOS-part



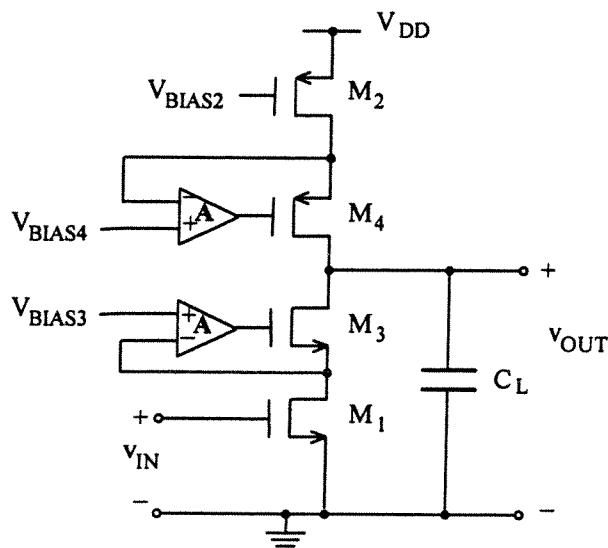
SSEC

PMOS-part



**COMMON-SOURCE AMPLIFIER  
WITH CASCODE. EXTRA BIAS**

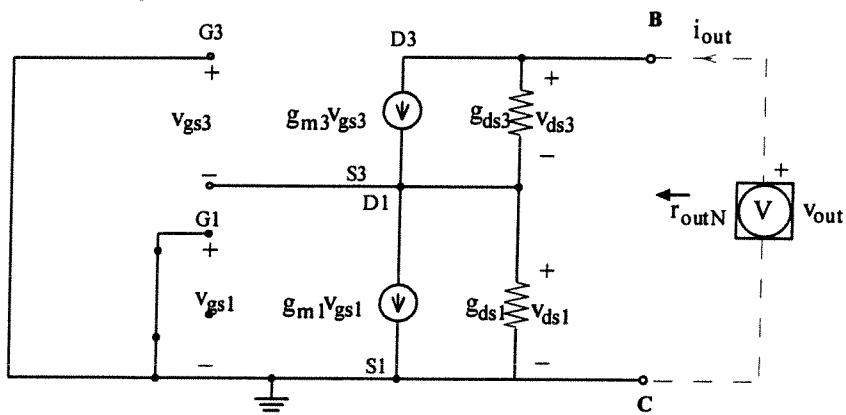
39



**Determine  $r_{out}$**

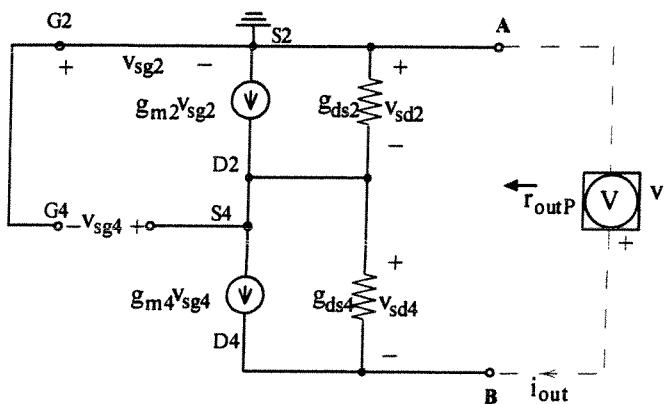
**SSEC**

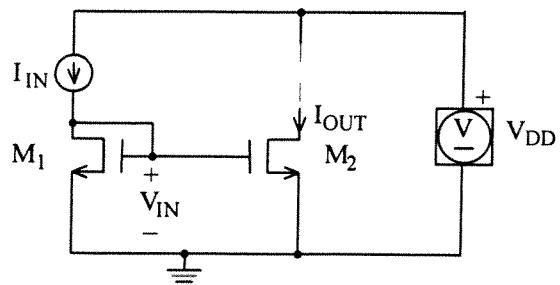
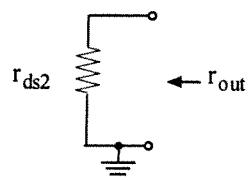
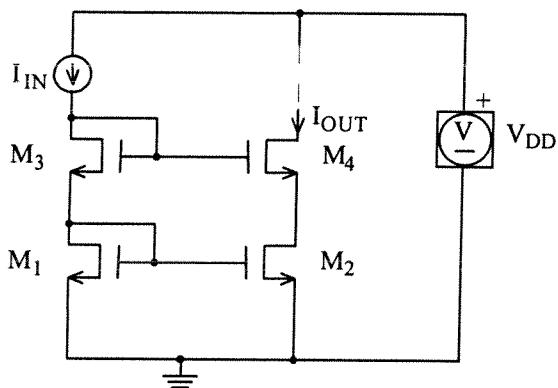
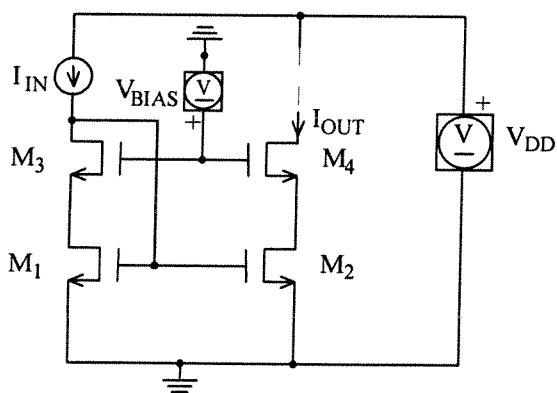
**NMOS-part**

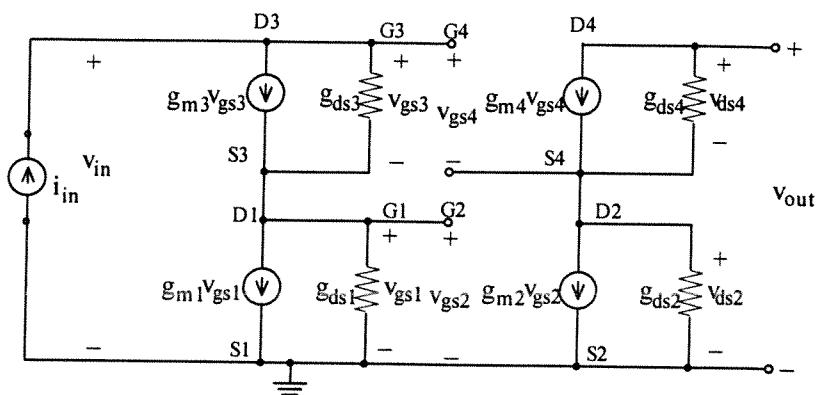
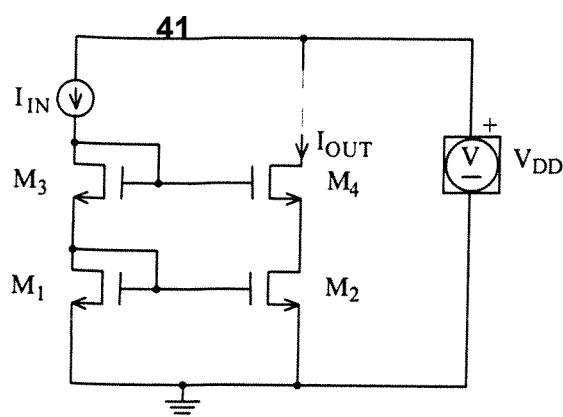


**SSEC**

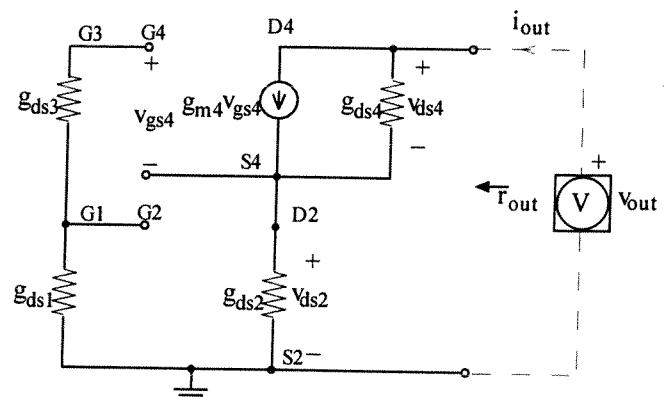
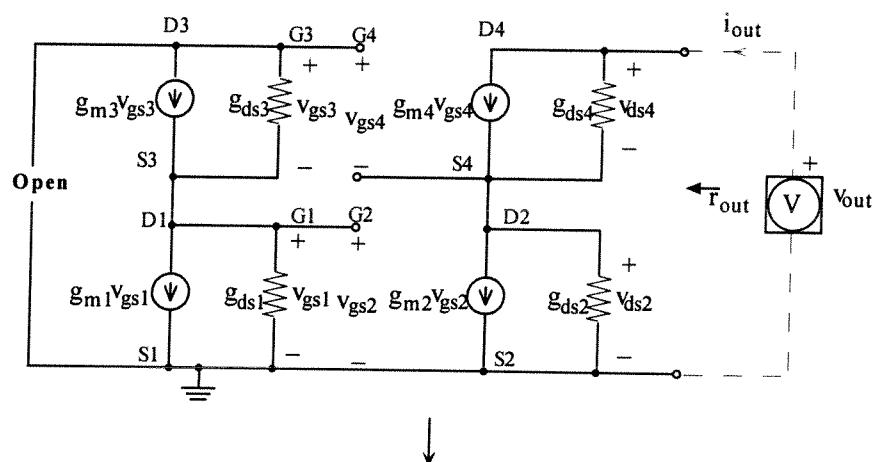
**PMOS-part**

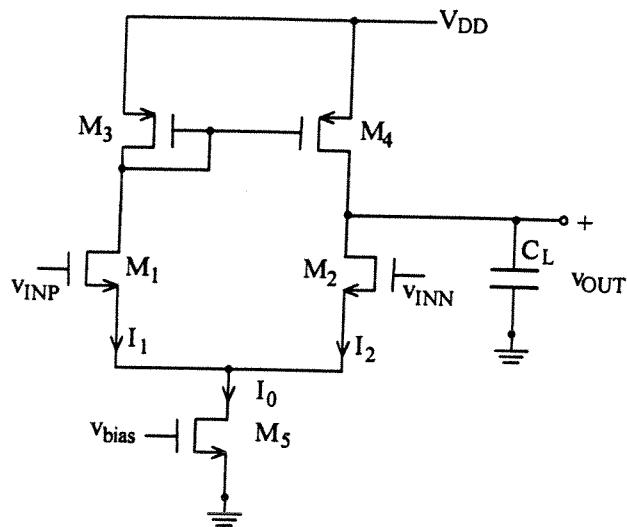


**CURRENT MIRROR****SMALL SIGNAL EQUIVALENT CIRCUIT (SSEC)****CASCODE CURRENT MIRROR****WIDE-SWING CURRENT MIRROR**



Determine  $r_{out}$



**DIFFERENTIAL GAINSTAGE**      (Large signal analysis)


**Assumptions:**

- 1) All transistors saturated
- 2)  $V_{INP} = V_{INN} = V_{IN}$  (COMMON MODE)

$$\text{CMR (Common Mode Range)} = [V_{IN \min}, V_{IN \max}]$$

$$\text{OR (Output Range)} = [V_{OUT \min}, V_{OUT \max}]$$

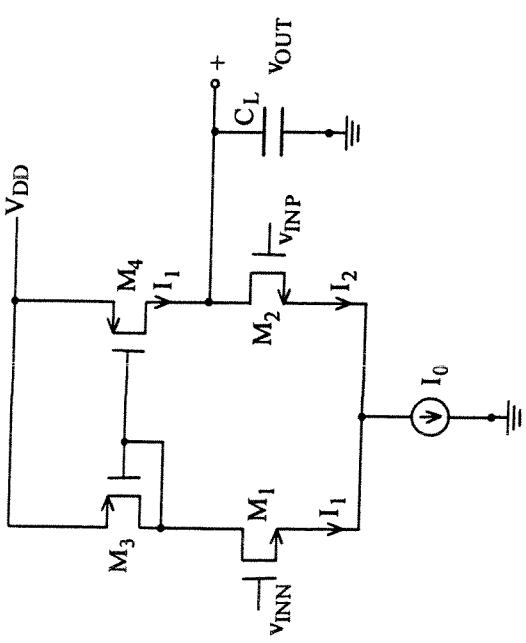
$$V_{IN \min} = V_{DS5} + V_{GS1} = V_{eff5} + V_{eff1} + V_{t1} = \sqrt{\frac{I_0}{\alpha_5}} + \sqrt{\frac{I_0/2}{\alpha_1}} + V_{t1}$$

$$\begin{aligned} V_{IN \max} &= V_{DD} - V_{SG3} - V_{DS1} + V_{GS1} = V_{DD} - V_{eff3} - V_{t3} - V_{eff1} + V_{eff1} + V_{t1} = \\ &= V_{DD} - \sqrt{\frac{I_0/2}{\alpha_3}} - V_{t3} + V_{t1} \end{aligned}$$

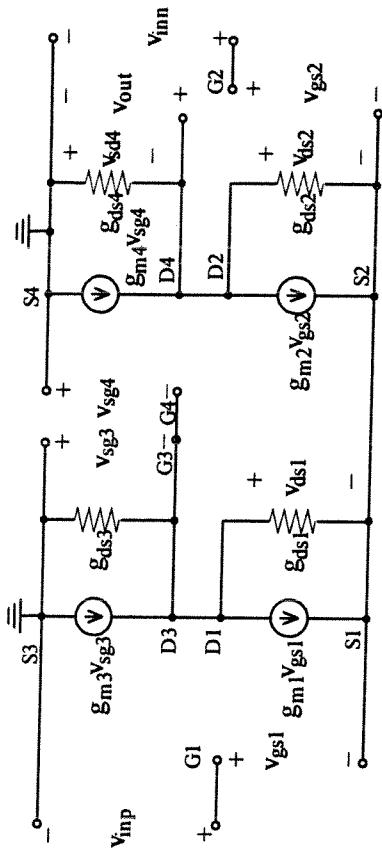
$$V_{OUT \min} = V_{DS5} + V_{DS2} = V_{eff5} + V_{eff1} = \sqrt{\frac{I_0}{\alpha_5}} + \sqrt{\frac{I_0/2}{\alpha_2}}$$

$$V_{OUT \max} = V_{DD} - V_{SD4} = V_{DD} - V_{eff4} = V_{DD} - \sqrt{\frac{I_0/2}{\alpha_4}}$$

### DIFFERENTIAL GAIN STAGE



SSEC



Determine  $\frac{v_{out}}{v_{inp} - v_{inn}}$  for differential gain stage.

- 1) Introduce variables  $v_x$  (at node x, i.e. node D1,D3) and  $v_y$  (at node y, i.e. node S1,S2).
- 2) Express  $v_{gs1}$ ,  $v_{gs2}$ ,  $v_{sg3}$  ( $= v_{sd3}$ ),  $v_{sg4}$ ,  $v_{ds1}$ ,  $v_{ds2}$ ,  $v_{sd4}$  in  $v_{inp}$ ,  $v_{inn}$ ,  $v_x$ ,  $v_y$  and  $v_{out}$ .

$$\begin{aligned} v_{gs1} &= v_{g1} - v_{s1} = v_{inp} - v_y & v_{ds1} &= v_x - v_y \\ v_{gs2} &= v_{g2} - v_{s2} = v_{inn} - v_y & v_{ds2} &= v_{out} - v_y \\ v_{sg3} &= -v_x & v_{sd3} &= v_{sg3} = -v_x \\ v_{sg4} &= v_{sg3} = -v_x & v_{sd4} &= -v_{out} \end{aligned}$$

- 3) Nodal analysis on node x, node out and gnd.

$$\text{Node x: } g_{m3}(-v_x) - g_{ds3}v_x - g_{m1}(v_{inp} - v_y) - g_{ds1}(v_x - v_y) = 0 \quad (1)$$

$$\text{Node out: } g_{m4}(-v_x) - g_{ds4}v_{out} - g_{m2}(v_{inn} - v_y) - g_{ds2}(v_{out} - v_y) = 0 \quad (2)$$

$$\text{gnd.: } -g_{m3}(-v_x) + g_{ds3}v_x - g_{m4}(-v_x) + g_{ds4}v_{out} = 0 \quad (3)$$

$$(3) \Rightarrow v_x = \frac{-g_{ds4}v_{out}}{g_{m3} + g_{m4} + g_{ds3}} \quad (4)$$

$$\begin{aligned} (1),(2) \Rightarrow & v_x(g_{m3} - g_{m4} + g_{ds3}) - g_{ds4}v_{out} + g_{m1}v_{inp} - g_{m2}v_{inn} - v_y(g_{m1} - g_{m2}) \\ & + g_{ds1}v_x - g_{ds2}v_{out} - v_y(g_{ds1} - g_{ds2}) = 0 \end{aligned} \quad (5)$$

- 4) Assume  $g_{ds1} = g_{ds2}$ ,  $g_{ds3} = g_{ds4}$ ,  $g_{m1} = g_{m2}$  and  $g_{m3} = g_{m4}$

$$(5) \Rightarrow v_x g_{ds4} - g_{ds4}v_{out} + g_{m1}(v_{inp} - v_{inn}) + g_{ds2}(v_x - v_{out}) = 0 \quad (6)$$

$$(4),(6) \Rightarrow g_{m1}(v_{inp} - v_{inn}) = v_{out}(g_{ds2} + \frac{g_{ds2}g_{ds4}}{g_{m3} + g_{m4} + g_{ds3}} + g_{ds4} + \frac{g_{ds4}^2}{g_{m3} + g_{m4} + g_{ds3}}) \quad (7)$$

But  $g_{ds3} = g_{ds4}$  and  $g_{m3} = g_{m4}$  which gives:

$$(7) \Rightarrow g_{m1}(v_{inp} - v_{inn}) = v_{out}(g_{ds2} + \frac{g_{ds2}g_{ds4}}{2g_{m4} + g_{ds4}} + g_{ds4} + \frac{g_{ds4}^2}{2g_{m4} + g_{ds4}}) \quad (8)$$

$$(8) \Rightarrow g_{m1}(v_{inp} - v_{inn}) = v_{out}g_{ds2}\left(1 + \frac{g_{ds4}}{2g_{m4} + g_{ds4}}\right) + v_{out}g_{ds4}\left(1 + \frac{g_{ds4}}{2g_{m4} + g_{ds4}}\right) \quad (9)$$

$$(9) \Rightarrow g_{m1}(v_{inp} - v_{inn}) = v_{out}\left(1 + \frac{g_{ds4}}{2g_{m4} + g_{ds4}}\right)(g_{ds2} + g_{ds4}) \quad (10)$$

$$(10) \Rightarrow g_{m1}(v_{inp} - v_{inn}) = v_{out}\left(\frac{2g_{m4} + 2g_{ds4}}{2g_{m4} + g_{ds4}}\right)(g_{ds2} + g_{ds4}) \quad (11)$$

---


$$(11) \Rightarrow \frac{v_{out}}{v_{inp} - v_{inn}} = \frac{g_{m1}(2g_{m4} + g_{ds4})}{2(g_{ds2} + g_{ds4})(g_{m4} + g_{ds4})} \approx \frac{g_{m1}}{g_{ds2} + g_{ds4}}$$

## PERFORMANCE MEASURES FOR DIFFERENTIAL GAIN STAGE

### LARGE SIGNAL ANALYSIS:

- Common Mode Range,  $CMR = [V_{inmin}, V_{inmax}]$
- Output range,  $OR = [V_{outmin}, V_{outmax}]$
- Slew Rate,  $SR = \max \left\{ \frac{dv_{out}}{dt} \right\}$

### SMALL SIGNAL ANALYSIS:

- Common Mode Rejection Ratio,  $CMRR = 20 \cdot 10 \log \frac{A_d}{A_{cm}}$
- Power Supply Rejection Ratio +,  $PSRR_+ = 20 \cdot 10 \log \frac{A_d}{A_{Vdd \rightarrow V_{out}}}$
- Power Supply Rejection Ratio -,  $PSRR_- = 20 \cdot 10 \log \frac{A_d}{A_{gnd \rightarrow V_{out}}}$

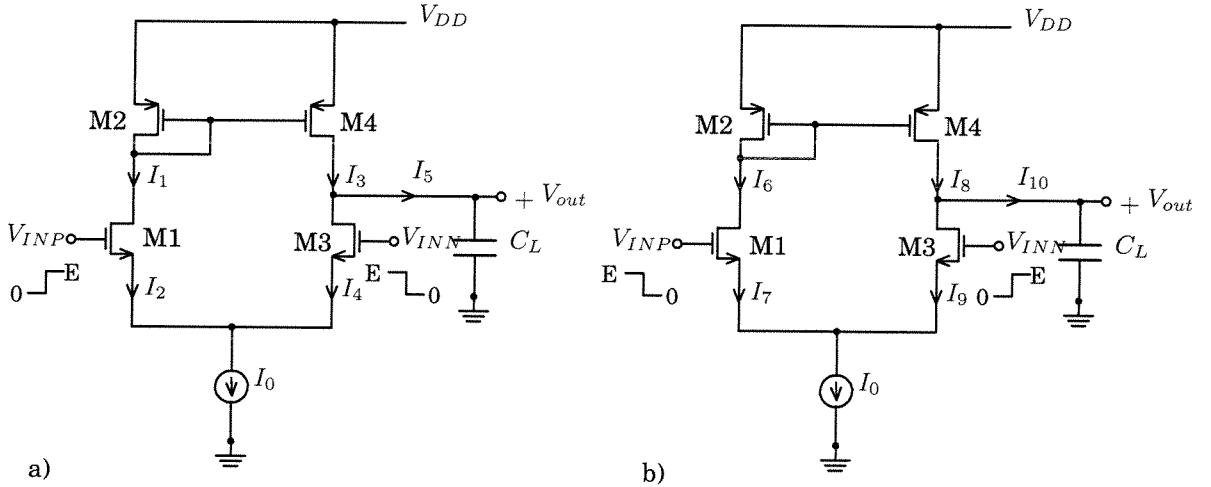
- $A_d$ =Amplification for differential input signals
- $A_{cm}$ =Amplification for common-mode input signals
- $A_{Vdd \rightarrow V_{out}}$ =Amplification for variations in  $+V_{dd}$  from  $V_{dd}$  to  $V_{out}$
- $A_{gnd \rightarrow V_{out}}$ =Amplification for variations in ground from ground to  $V_{out}$

To determine  $A_{Vdd \rightarrow V_{out}}$  set the AC-input signal to zero and introduce an AC-source at  $V_{dd+}$ .  $A_{gnd \rightarrow V_{out}}$  determines in the same way by setting the AC-input signal to zero and introduce an AC-source at  $V_{dd-}$  (ground).

### DETERMINATION OF SLEW-RATE

To determine Slew-Rate (SR) for the differential gain-stage below, apply a square-pulse on  $V_{INP}$  and an inverted square-pulse on  $V_{INN}$ . Figure a) gives phase I, when  $V_{INP}$  grows instantaneously from 0 to  $E$  and  $V_{INN}$  at the same time instantaneously goes from  $E$  to 0. Figure b) shows phase II that starts with  $V_{INP}$  instantaneously decreasing from  $E$  to 0 and  $V_{INN}$  instantaneously increasing from 0 to  $E$ .

$E$  is larger than  $V_{tn}$  ( $E > V_{tn}$ ). Transistors M1 and M3 are identical as well as M2 and M4.



**Phase I:**

- $V_{INP} = +E, V_{INN} = 0 \Rightarrow M1$  conducts and  $M3$  blocks.
- $M3$  blocks  $\Rightarrow I_4 = 0$
- $M1$  conducts  $\Rightarrow I_1 = I_2 = I_0$
- $M2$  and  $M4$  is a current mirror and as  $M2$  and  $M4$  are identical  $I_3 = I_1 = I_0$
- $M3$  blocks ( $I_4 = 0$ )  $\Rightarrow I_5 = I_3 = I_0$

**Phase II:**

- $V_{INP} = 0, V_{INN} = +E \Rightarrow M1$  blocks and  $M3$  conducts.
- $M1$  blocks  $\Rightarrow I_6 = I_7 = 0$
- $M2$  and  $M4$  is a current mirror  $\Rightarrow I_8 = I_6 = 0$
- $M3$  conducts  $\Rightarrow I_9 = I_0$
- $I_8 = 0$  and  $I_9 = I_0 \Rightarrow I_{10} = -I_9 = -I_0$

$$\text{Definition: Slew-Rate (SR)} = \max \frac{dv_{out}(t)}{dt}$$

For capacitor  $C_L$ :

$$i_{CL}(t) = C_L \frac{dv_{CL}(t)}{dt} = C_L \frac{dv_{out}(t)}{dt} \Rightarrow \frac{dv_{out}}{dt} = \frac{i_{CL}(t)}{C_L}$$

Thus, maximum value of  $\frac{dv_{out}(t)}{dt}$  obtains for maximum value of  $i_{CL}(t)$ , which has been shown above to be  $I_0$ .

$$\text{I.e. Slew-Rate} = \underline{\underline{\frac{I_0}{C_L}}}$$

## NOISE

Look at a signal voltage  $v(t)$  that interferes from a noise voltage  $v_n$ , which means that  $v_{tot}(t) = v(t) + v_n(t)$ . The power of the signal denotes  $P_{signal}$  and the power of the noise  $P_{noise}$ .

Following performance measures is defined:

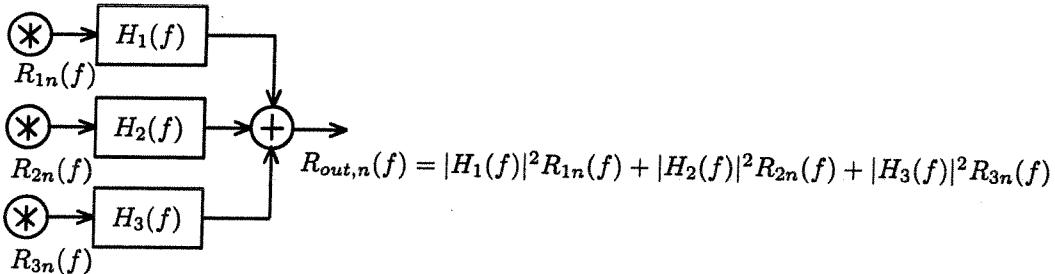
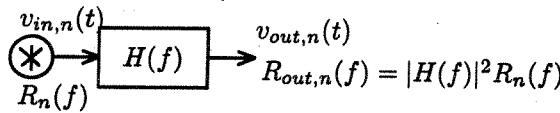
- Signal Noise Ratio,  $SNR = 10 \cdot 10 \log \frac{P_{signal}}{P_{noise}}$
- Dynamic Range,  $DR = 20 \cdot 10 \log \frac{|v_{in,max}(t)|}{|v_{in,min}(t)|}$
- If  $|v_{in}(t)| > |v_{in,max}(t)|$  you get distortion.
- If  $|v_{in}(t)| < |v_{in,min}(t)|$  the signal gets drowned in the noise.
- Noise power,  $P_{noise}$ , defines as  $P_{noise} = \frac{1}{T} \int_0^T v_n^2(t) dt$
- Also, if  $V_n(f)$  is the Fourier transform of  $v_n(t)$ ,  $P_{noise} = \int_{-\infty}^{\infty} V_n^2(f) df$
- $V_n^2(f)$  is the *spectral density*  $R_n(f)$  and  $R_n(f)$  is the Fourier transform of the *autocorrelation function*  $r_n(t)$ . I.e.  $V_n^2(f) = R_n(f) = \mathcal{F}\{r_n(t)\}$

If the input signal to a linear system, with transfer function  $H(f)$ , has a noise component with spectral density  $R_n(f)$  the output signal will get a noise component with spectral density  $R_{out,n}(f)$  and

$$R_{out,n}(f) = |H(f)|^2 R_n(f)$$

If we have say three systems,  $H_1(f)$ ,  $H_2(f)$  and  $H_3(f)$  with noise,  $R_{1n}(f)$ ,  $R_{2n}(f)$  and  $R_{3n}(f)$  respectively, on their inputs and the noise sources are *uncorrelated*, and if the output signals from the systems are added the spectral density of the output signal will be:

$$R_{out,n}(f) = |H_1(f)|^2 R_{1n}(f) + |H_2(f)|^2 R_{2n}(f) + |H_3(f)|^2 R_{3n}(f)$$



### Noise bandwidth concept

Regard a one-pole system with transfer function

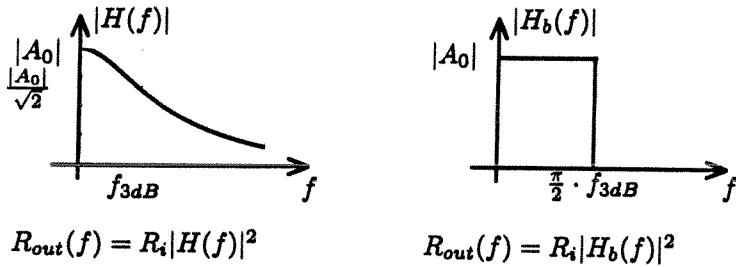
$$H(s) = \frac{A_0}{1 + \frac{s}{p_1}} \Rightarrow |H(f)| = \frac{|A_0|}{\sqrt{1 + \left(\frac{2\pi f}{p_1}\right)^2}}$$

This equation gives the 3dB cut-off frequency:  $f_{3dB} = \frac{|p_1|}{2\pi}$ .

If you feed the system with *white noise*, that is noise with constant (independent of  $f$ ) spectral density  $R_i(f) = R_i$ , the noise power on the output will be

$$\begin{aligned} P_{out,noise} &= \int_0^\infty |H(f)|^2 R_i df = R_i \int_0^\infty \frac{|A_0|^2}{1 + \left(\frac{2\pi f}{p_1}\right)^2} = R_i \cdot \frac{|A_0|^2 |p_1|}{2\pi} \left[ \arctan \frac{2\pi f}{|p_1|} \right]_0^\infty \\ &= R_i \cdot \frac{|A_0|^2 |p_1|}{2\pi} \cdot \frac{\pi}{2} = R_i |A_0|^2 \cdot \frac{\pi}{2} \cdot \frac{|p_1|}{2\pi} = R_i |A_0|^2 \cdot \frac{\pi}{2} \cdot f_{3dB} \end{aligned}$$

If you have a *brick-wall filter* with  $|H_b(f)| = |A_0|$  and bandwidth  $\frac{\pi}{2} \cdot f_{3dB}$  you get the same power  $P_{out,noise}$ . Therefore  $\frac{\pi}{2} \cdot f_{3dB}$  is said to be the **noise-bandwidth** of this one-pole system.



### Noise in CMOS-circuits

Noise in CMOS-circuits is *inherent noise*, not *interference noise*. There are three different types of inherent noise.

- 1) Thermal noise - due to thermal excitation of charge carriers. Thermal noise is white noise.
- 2) Flicker noise - due to traps in the semiconductor that hold carriers, which normally gives the DC-current, for some while and than release them. (DC-current doesn't float smooth.)  $R_n(f) \sim \frac{1}{f}$  (more accurate  $R_n(f) \sim \frac{1}{f^\alpha}$  where  $0.8 < \alpha < 1.3$ ).
- 3) Shot noise - DC-current is a result of individual carriers, which yields a current that actually is pulsed and not smooth.

**Noise models CMOS:** (Regard the saturated region)

Flicker noise (spektral density  $V_g^2(f) = \frac{K}{WLC_{ox}f}$ ) and thermal noise (spectral density  $I_d^2(f) = 4kT\left(\frac{2}{3}\right)g_m$ ) dominates in CMOS-circuits.

As  $i_d(t) \approx g_m v_{gs}(t)$  then  $I_d(f) \approx g_m V_{gs}(f)$  and the thermal noise with spectral density  $I_d^2(f) = 4kT\left(\frac{2}{3}\right)g_m$  can be transformed to an equivalent noise voltage on the input with the spectral density  $V_{gs}^2(f) = 4kT\left(\frac{2}{3}\right)\frac{1}{g_m}$ .  $V_g^2(f)$  and  $V_{gs}^2(f)$  are uncorrelated and can thus be added.

<b>MOSFET</b>  <b>(Active region)</b>	$V_g^2(f) = \frac{K}{WLC_{ox}f}$ $I_d^2(f) = 4kT\left(\frac{2}{3}\right)g_m$	$V_I^2(f) = 4kT\left(\frac{2}{3}\right)\frac{1}{g_m} + \frac{K}{WLC_{ox}f}$ <p style="text-align: center;">Simplified model for low and moderate frequencies</p>
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